SCLS143B - DECEMBER 1982 - REVISED MAY 1997

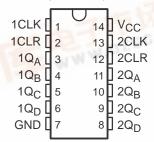
- Dual 4-Bit Binary Counters With Individual Clocks
- Direct Clear for Each 4-Bit Counter
- Can Significantly Improve System
 Densities by Reducing Counter Package
 Count by 50 Percent
- Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

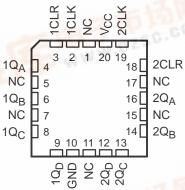
The 'HC393 contain eight flip-flops and additional gating to implement two individual 4-bit counters in a single package. The 'HC393 comprise two independent 4-bit binary counters, each having a clear (CLR) and a clock (CLK) input. N-bit binary counters can be implemented with each package, providing the capability of divide by 256. The 'HC393 have parallel outputs from each counter stage so that any submultiple of the input count frequency is available for system timing signals.

The SN54HC393 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74HC393 is characterized for operation from -40°C to 85°C.

SN54HC393 . . . J OR W PACKAGE SN74HC393 . . . D, DB, OR N PACKAGE (TOP VIEW)



SN54HC393 . . . FK PACKAGE (TOP VIEW)



NC – No internal connection



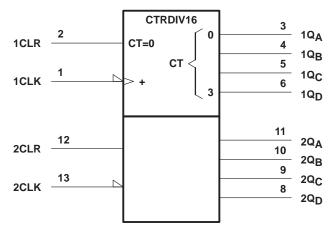
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FUNCTION TABLE COUNT SEQUENCE (each counter)

COUNT		OUTI	PUTS	
COUNT	Q_{D}	QС	Q_{B}	Q_{A}
0	L	L	L	L
1	L	L	L	Н
2	L	L	Н	L
3	L	L	Н	Н
4	L	Н	L	L
5	L	Н	L	Н
6	L	Н	Н	L
7	L	Н	Н	Н
8	Н	L	L	L
9	Н	L	L	Н
10	Н	L	Н	L
11	Н	L	Н	Н
12	Н	Н	L	L
13	Н	Н	L	Н
14	Н	Н	Н	L
15	Н	Н	Н	Н

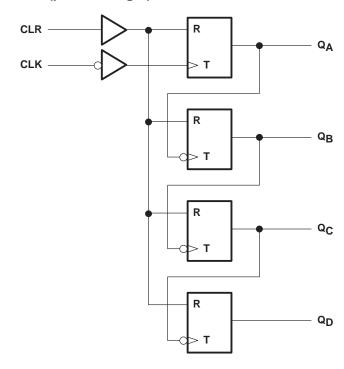
logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, DB, J, N, and W packages.



logic diagram, each counter (positive logic)



absolute maximum ratings over operating free-air temperature range†

Supply voltage range, V _{CC}		
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (se	ee Note 1)	±20 mA
Output clamp current, IOK (VO < 0 or VO > VCO	c) (see Note 1)	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})		±25 mA
Continuous current through V _{CC} or GND		±50 mA
Package thermal impedance, θ_{JA} (see Note 2):		
•	DB package	158°C/W
	N package	78°C/W
Storage temperature range, T _{stq}		

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

^{2.} The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

SN54HC393, SN74HC393 DUAL 4-BIT BINARY COUNTERS

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recommended operating conditions

			SI	SN54HC393			174HC39	3	UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage		2	5	6	2	5	6	V
		V _{CC} = 2 V	1.5			1.5			
VIH	High-level input voltage	V _{CC} = 4.5 V	3.15			3.15			V
		VCC = 6 V	4.2			4.2			
		V _{CC} = 2 V	0		0.5	0		0.5	
VIL	Low-level input voltage	V _{CC} = 4.5 V	0		1.35	0		1.35	V
		VCC = 6 V	0		1.8	0		1.8	
٧ _I	Input voltage		0		VCC	0		VCC	V
٧o	Output voltage		0		V_{CC}	0		VCC	V
		V _{CC} = 2 V	0		1000	0		1000	
t _t †	Input transition (rise and fall) time	V _{CC} = 4.5 V	0		500	0		500	ns
		VCC = 6 V	0		400	0		400	
T _A	Operating free-air temperature		-55		125	-40		85	°C

[†] If this device is used in the threshold region (from V_{IL} max = 0.5 V to V_{IH} min = 1.5 V), there is a potential to go into the wrong state from induced grounding, causing double clocking. Operating with the inputs at t_t = 1000 ns and V_{CC} = 2 V does not damage the device; however, functionally, the CLK inputs are not ensured while in the shift, count, or toggle operating modes.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS		Vac	Т	T _A = 25°C			C393	SN74HC393		UNIT
PARAMETER	TEST CC	MUITIONS	vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	1.9	1.998		1.9		1.9		
		$I_{OH} = -20 \mu A$	4.5 V	4.4	4.499		4.4		4.4		
Voн	$V_I = V_{IH}$ or V_{IL}		6 V	5.9	5.999		5.9		5.9		V
		$I_{OH} = -4 \text{ mA}$	4.5 V	3.98	4.3		3.7		3.84		
		$I_{OH} = -5.2 \text{ mA}$	6 V	5.48	5.8		5.2		5.34		
		I _{OL} = 20 μA	2 V		0.002	0.1		0.1		0.1	
			4.5 V		0.001	0.1		0.1		0.1	
VOL	VI = VIH or VIL		6 V		0.001	0.1		0.1		0.1	V
		I _{OL} = 4 mA	4.5 V		0.17	0.26		0.4		0.33	
			6 V		0.15	0.26		0.4		0.33	
lį	$V_I = V_{CC}$ or 0		6 V		±0.1	±100		±1000		±1000	nA
Icc	$V_I = V_{CC}$ or 0,	IO = 0	6 V			8		160		80	μΑ
Ci			2 V to 6 V		3	10		10		10	pF

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timing requirements over recommended operating free-air temperature range (unless otherwise noted)

			Vaa	T _A = 1	25°C	SN54F	IC393	SN74H	IC393	UNIT
			V _{CC}	MIN	MAX	MIN	MAX	MIN	MAX	
			2 V	0	6	0	4.2	0	5	
fclock	Clock frequency		4.5 V	0	31	0	21	0	25	MHz
			6 V	0	36	0	25	0	MAX 5	
		CLK high or low	2 V	80		120		100		ns
Date days for			4.5 V	16		24		20		
	Pulse duration		6 V	14		20		18		
t _W	Fulse duration	CLR high	2 V	80		120		100		
			4.5 V	16		24		20		
			6 V	14		20		18		
		•	2 V	25		25		25		
t _{SU} Setup time, CLR inactive	Setup time, CLR inactive		4.5 V	5		5		5		ns
			6 V	5		5		5	·	

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

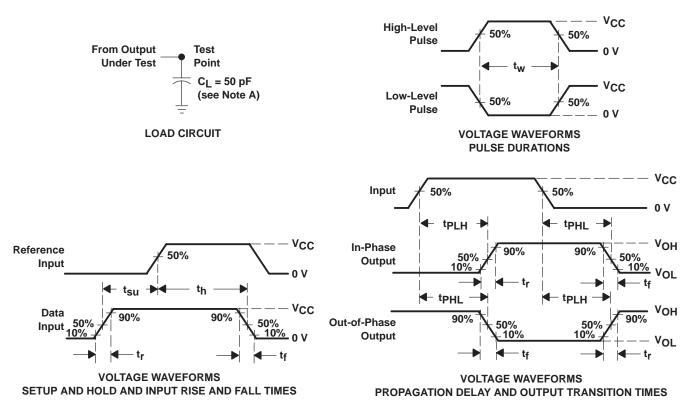
PARAMETER	FROM	TO (OUTPUT)	Vaa	T,	_Δ = 25°C	;	SN54H	IC393	SN74H	IC393	UNIT
PARAMETER	(INPUT)		Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	
			2 V	6	10		4.2		5		
f _{max}	CLK	Q_A	4.5 V	31	50		21		25		MHz
			6 V	36	60		25		28		
			2 V		50	120		180		150	
		Q_A	4.5 V		15	24		36		30	
			6 V		13	20		31		26	
			2 V		72	190		285		240	
	CLK	Q _B	4.5 V		22	38		57		47	ns
			6 V		18	32		48		40	
^t pd	CLK		2 V		91	240		360		300	
		QC	4.5 V		28	48		72		60	
			6 V		22	41		61		51	
			2 V		100	290		430		360	
		Q_{D}	4.5 V		32	58		87		72	
			6 V		24	50		74		62	
			2 V		45	165		250		205	
t _{PHL}	CLR	Any	4.5 V		17	33		49		41	ns
			6 V		14	28		42		35	
			2 V		28	75		110		95	
t _t		Any	4.5 V		8	15		22		19	ns
			6 V		6	13		19		16	

operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance per counter	No load	40	pF



PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and test-fixture capacitance.

- B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_r = 6 \text{ ns}$.
- C. For clock inputs, f_{max} is measured when the input duty cycle is 50%.
- D. The outputs are measured one at a time with one input transition per measurement.
- E. tpl H and tpHI are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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